Development and characterization of hybrid photodetector based on MCP and an embedded Timepix4 ASIC anode



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Overview

- Project overview
- The hybrid detector operating principle
- The Timepix4 ASIC
- DAQ and software
- Ceramic carriers quality tests
- MCP-PMT preliminary tests
 - gain measurements
 - timing measurements



Project recap - Novel hybrid photon detector

- "Hybrid" assembly based on tube kept under high vacuum
- > Photocathode deposited in the inner part of the input window
- MCP stack (Chevron configuration)
- Pixelated CMOS anode: Timepix4 ASIC

Ceramic carrier board

- interface between inner/outer parts of the detector
- custom Pin Grid Array for I/O signals
- Heat sink (ASIC power 5 W)
- > **PCBs** to connect the detector to a FPGA-based DAQ system

Proof of concept: use of a bare ASIC inside a vacuum tube with a microchannel plate (MCP) already demonstrated

- optical imaging tube based on Medipix2 ASIC [Proc. SPIE 7021 2008 (J. Vallerga, A. Tremsin et al.)]
- optical imaging tube with a quad Timepix readout [JINST 9 C05055 2014 (J. Vallerga, A. Tremsin et al.)]



[M. Fiorini et al, JINST 13 (2018) C12005]





Photon conversion producing a photo-electron in a high Quantum Efficiency (QE) photocathode

The photo-electron is transported by a drift electric field onto a microchannel plate (MCP) in Chevron configuration

The electrons cloud produced by the MCP is carried by another drift field onto the input (bump-bonding) pads of a bare Timepix4 ASIC, where it is sensed as a charge pulse by the read-out electronics

The Timepix4 ASIC will amplify, discriminate and digitize the MCP signal inside the vacuum tube



Single-photon

Pixelated anode

Pixelated anode: Timepix4 ASIC

- > ASIC in 65 nm CMOS
 - Developed by Medipix4 collaboration
- > 512 × 448 pixels (55 μ m × 55 μ m each)
- Large active area: 7 cm²
- Bump pads used as anode 24700 µm





- Signal from MCP amplified and discriminated
- Time-stamp provided by Time-to-Digital Converter (TDC) based on Voltage-Controlled Oscillator (VCO)
 - 195 ps bin size (~ 56 ps r.m.s. resolution) for Time-of-Arrival (ToA) measurements
 - **1.56 ns** bin size for Time-over-Threshold (ToT) measurements

High rate capability:

- maximum bandwidth: 160 Gb/s
- maximum hit rate: 2.5 Ghits/s/chip

Output:

- 64 bits of data per hit with 64b/66b encoding
- transmitted via 16 high-speed links up to 10.24 Gbps

X. Llopart et al 2022 JINST 17 C01044

Data Acquisition (DAQ) system

- Data driven front-end electronics
 - 64 bits for each pixel hit
 - 40 MHz slow control
 - 16 x 10.24 Gb/s fast serial links
- FPGA-based control board:
 - detector configuration
 - serial data decoding
 - sends pre-processed data to server to store them for post-processing
- DAQ server
 - receives and decodes data from control board
 - data analysis
 - data storage



Timepix4 characterization measurements - VCO calibration

- On pixel VCO oscillation frequency controlled by a PLL at the center of the chip (@ 640 MHz nominal)
- It has been measured that on pixel VCO oscillate around 640 MHz with a spread of around 40 MHz





Timepix4 characterization measurements - VCO calibration

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- It has been measured that on pixel VCO oscillate around 640 MHz with a spread of around 40 MHz
- Spread caused by power supply dispersion due to large size and wire bonds: large improvements expected with TSV
- Finer ToA bins generated with different width
- Timing performances heavily affected by this effect
- Internal test pulse tool exploited to calibrate
 VCO frequencies for the whole matrix (28672 VCO)



arXiv:2404.15499

- At fixed charge, large ToT spread across the matrix
- Analog testpulse
- Non linear calibration
- Threshold set to 1 ke⁻



- At fixed charge, large ToT spread across the matrix
- Analog testpulse
- Non linear calibration
- Threshold set to 1 ke⁻
- Per-pixel calibration done over the whole matrix
- Automatic algorithm exploiting fast read-out
- Calibration fit parameters distribution



 $ToT(Q) = p_0 + p_1 Q + p_2 / (p_3 + Q)$

ToT vs Q calibration

• Validation with radioactive sources(¹³⁷Cs and ²⁴¹Am superimposed spectra)



Timing resolution measurements - Laser measurements

Spidr4 control board

Spidr4 control board

Timepix4v2:

- bonded to a 100 μm n-on-p Si detector biased at -150 V
- metalization with holes pattern
- Courtesy of CERN and NIKHEF Medipix4/VELO groups

Waveform generator

- input signal to digital pixels
- laser trigger

Laser:

- o 1060 nm
- variable attenuator



To digital pixels

Pulse generator Active Technologies PG-1072 (interchannel jitter ~7 ps r.m.s.)



Period: 5 ms Amplitude: 1.2 V



Laser variable Attenuator



Pulsed Diode Laser PDL 800-B

Single pixel timing resolution

- Laser focused using micro-collimator:
 - \circ spot size = 77 μ m
- Laser spot in **fixed position** for all presented measurements
- Measurements using variable laser attenuation, populating a wide charge range on each pixel
- Different time walk trends on different pixels
- Time walk corrected separately on each pixel



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- Distribution of timing resolution as a function of injected charge
- For the pixel [305,144], where the laser is focused, the standard deviation saturates at 129±2 ps rms
- Subtracting the contribution of the reference signal (72 ps), a resolution of 107±3 ps rms is obtained

- For each cluster (~30 pixels):
 - weighted average of ToA using charge as weights
 - cluster charge computed
- Timing resolution dependency on cluster charge:
 - best result: $\sigma_{ToADiffAvg} = 79 \pm 1 ps rms$
 - timing resolution subtracting reference signal contribution:
 σ_{ToAAvg}=33 ± 3 ps rms



Ceramic carrier

- Custom design and Pin Grid Array (PGA) by INFN and Kyocera
- Produced by Kyocera
- Timepix4 planarity measurements
- Electrical continuity measurements
- Ceramic characterization through Timepix4:
 - Timepix4 diagnostic:
 - per-pixel digital test
 - DACs diagnostic
 - power supply measurements
 - DLL columns and ADBs check
 - Test-pulses measurements, to verify both test-pulse and data-readout
 - \circ High-speed links configuration



- Prototype vacuum tube produced by Hamamatsu HPK
 - \circ first prototypes received one month ago
- > Main characteristics:
 - Multi-alkali S20 photocathode
 - peak QE > 30% at 380 nm
 - \circ 6 μ m MCP channel diameter (7.5 μ m pitch)
- Several variants for complete characterization
 - 2-MCP stack and 3-MCP stack
 - \circ 1d 2d 3d end-spoiling





MCP-PMT characterization measurements - Setup

- Tube prototypes (2-MCP stack with 2d end-spoiling) received from Hamamatsu HPK mounted on custom carrier board within a **dark box**
- Cooling system to maintain stable temperature inside the tube
- Dry air fluxed in the dark box to decrease the internal dew point



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- Cooling system to maintain stable temperature inside the tube
- Dry air fluxed in the dark box to decrease the internal dew point
- Control board and DAQ PC outside the box with 1 m flat FMC cable connection
 - Developed by INFN Ferrara:
 - \circ based on commercial dev. kit Xilinx KCU105
 - firmware, FMC adaptor and carrier board
- Remote monitoring and control of HV and current values



- Gain and dark count rate (DCR) measurements performed on dark noise acquisitions
- \succ MCP_{out}- MCP_{in} scan with 100 V step
- Different threshold levels used (1000 e-, 1500 e-, 3000 e-)
- Per-pixel ToT calibration not done yet
 - average calibration used
- Relative gain obtained both from clusters charge and pads on ceramic carrier
- Gain trend from clusters compatible with pads one



MCP-PMT characterization measurements - Dark conditions

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Gain trend comparison between Tpx4 and ceramic pads





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Laser setup:

- 405 nm
- variable attenuator
- exploring both single photon and multiple photons regimes
- Ongoing analysis:
 - Time-walk correction procedure
 - Single-pixel timing resolution (exploring low-charge range)





Next steps

- Improvements of ceramic carrier and MCP-PMT quality tests:
 - fast links diagnostic
 - MCP-PMT measurements to be optimized for in-spec HV parameters
- Further studies on dark count rate and uniformity
- \succ Timing resolution:
 - analysis to be completed for multiple and single photon measurements
 - cluster timing resolution analysis to be included
- Test-beam preparation with Cherenkov setup ongoing
 - Beam time allocated SPS H8 (October 2024)

Conclusions

We are developing a new detector for single photons in the visible range:

- Vacuum tube with MCP and Timepix4 CMOS ASIC as anode
- ➤ Funded by the European Research Council (G.A. No. 819627)
- Complete integration of sensor and electronics (internal data processing and data transmission)

Promising results characterizing Timepix4 bonded to Si sensor (arXiv:2404.15499):

- ➢ ToT vs Q per pixel calibration
- > single pixel timing resolution: $\sigma_{TOA} = 107 \pm 3 \text{ ps rms}$
- > cluster timing resolution: $\sigma_{TOA} = 33 \pm 3 ps rms$

Preliminary measurements on MCP-PMT first prototypes:

- gain measurements through Timepix4 and oscilloscope
- expected gain dependance on MCP voltage
- dark count rate under study
- timing resolution through laser setup under study







Thanks for your attention

Thanks to the CERN for the support









Backup





Detector operating principle: photocatode

Photon conversion producing a photo-electron in a high Quantum Efficiency (QE) photocatode

- high QE in blue-green region (for Cherenkov photons)
- \blacktriangleright low dark count rate (10²-10³ Hz/cm² @300K)
- > large active area

Flexible design to use different photocatodes if needed for various applications



Detector operating principle: microchannel plate

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- pore spacing of 5-10 μm to improve spatial and timing resolution, and hit rate
- short photocathode-to-MCP distance to improve spatial and timing resolution
- MCP-to-anode distance tuned for optimized spatial and timing resolution
- possible options to increase lifetime:
 - MCP operated at low gain (10^4 - 10^5)
 - Atomic Layer Deposition (ALD)



Detector operating principle: pixelated anode

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DAC V scan

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AEOC VDDA-GNDA

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 - High-speed links configuration



- Previous cooling system: liquid cooling with a cold finger on the bottom face of the ceramic carrier
 - MCP and photocatode temperature still too high when Timepix4 operates
- Improved cooling system: additional copper ring in thermal contact with quartz window to extract heat from both tube sides
- More efficient cooling: tube temperature reaching about 5°C when thermal equilibrium is reached
- Increases of about 2°C on outer flange when Timepix4 reaches 5 W power consumption



Power consumption and cooling

- > Timepix4 power consumption \sim 5 W
- Goal: stable operation with 20°C inside the vacuum tube
 - Cold finger attached to the ceramic carrier



- Packet decoding
- Clustering algorithm:
 - DBSCAN algorithm
 - variable spatial and timing parameters to gather hits on the same cluster
- ToA of each hit compared with the reference ToA of the associated digital pixel signal



MCP-PMT characterization measurements - Preliminary procedures

- Temperature inside dark box monitored through termo-couples in 4 points:
 - carrier PCB
 - tube flange (< 7°C when Timepix4 is acquiring)
 - chiller in branch and chiller out branch (about 3°C and 3.5°C)
- Humidity monitoring (about 5%)
- Timepix4 diagnostic repeated after MCP-PMT mounting, in vacuum conditions after phototube baking
- Frame based threshold equalization
- > VCO calibration procedure



Cluster timing resolution selecting a shell of pixels

- Large improvement in the resolution from 1-pixel clusters to 5-pixels clusters
- > Small or negligible improvement increasing further the cluster size



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MCP-PMT limitation

- MCP-PMT lifetime limited by the integrated anode charge, which leads to a strong QE reduction
 - From 0.2 C/cm² to >30 C/cm² in recent years thanks to ALD
- With the expected photon hit rate (~10 MHz/mm²), assuming a 10⁴ gain (very conservative), and an operation of 10 years with 25% duty cycle we have:
 - Total IAC ~120 C/cm²
 - Anode current density ~2 μA/cm²
- ALD coating is based on the deposition of resistive and/or secondary emissive layers (could tune MCP properties)
 - Reported adverse effects on saturation current on some model with ALD
- Strong R&D to find the best "recipe" is needed



[D. Miehling et al., NIM A 1049 (2023) 168047]